



**LUMAWISE Endurance S2 Connector Platform**

**1. SCOPE**

1.1. Content

This specification covers performance, tests and quality requirements for the TE connectivity LUMAWISE Endurance S Gen 2 connector platform for roadway and area lighting applications.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

1.3. Qualification Test Results

Successful qualification testing on the subject product line has not been completed. The Qualification Test Report number will be issued upon successful qualification testing.

**2. APPLICABLE DOCUMENTS AND FORMS**

The following documents and forms constitute a part of this specification to the extent specified herein. Unless otherwise indicated, the latest edition of the document applies.

2.1. TE Documents

- [114-160106](#): Application Specification
- [501-161262](#): Qualification Test Report
- 109-197: Test Specification (TE Test Specification vs EIA and IEC Test Methods)

2.2. Industry Documents

- EIA-364: Electrical Connector/Socket Test Procedures Including Environmental Classifications
- IEC-60512-11-6: Connectors for Electronic Equipment - Corrosion, salt mist
- IEC-60529: Degrees of Protection Provided by Enclosures (IP Code)
- IEC 62262: Degrees of Protection Provided by Enclosures Against External Mechanical Impacts

**3. REQUIREMENTS**

3.1. Design and Construction

Product shall be of the design, construction, materials, and physical dimensions specified on the applicable product drawing.

3.2. Ratings

Voltage	Current	Temperature
250 volts VAC/VDC	5.0A	-40 to 90°C

3.3. Test Requirements and Procedures Summary

Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

TEST DESCRIPTION	REQUIREMENT	PROCEDURE									
Initial examination of product	Meets requirements of product drawing.	EIA-364-18. Visual and dimensional (C of C) inspection per product drawing.									
Final examination of product	Meets visual requirements.	EIA-364-18. Visual inspection.									
<b>ELECTRICAL</b>											
Low Level Contact Resistance (LLCR).	Δ25 milliohms maximum.	EIA-364-23. Subject specimens to 100 milliamperes maximum and 20 millivolts maximum open circuit voltage. See Figure 4.									
Insulation Resistance.	100 mega ohms minimum initial. 10 mega ohms minimum final.	EIA-364-21. 500 volts DC, 2-minute hold. Test between adjacent contacts of mated specimens.									
Withstanding Voltage – Internal.	One-minute hold with no breakdown or flashover.	EIA-364-20, Condition I. 1600 volts AC at sea level. Test performed between adjacent contacts of mated specimens.									
Temperature Rise vs Current.	30°C maximum temperature rise at specified current (100% energized). Refer to section 3.2 for current value.	EIA-364-70, Method 1; Stabilize at a single current level until 3 readings at 5-minute intervals are within 1°C.									
Withstand voltage – External.	One-minute hold with no breakdown or flashover.	EIA-364-20, Condition I; 10,000 volts AC at sea level. Test performed between contacts and receptacle mounting plate of mated specimens.									
<b>MECHANICAL</b>											
Random Vibration.	No discontinuities of 1 microsecond or longer duration. See Note (a).	EIA-364-28, Test Condition VII, Test Condition Letter E; Subject mated specimens to 20 to 500 Hz random levels at 4.9g. 90 minutes in each of 3 mutually perpendicular planes.									
Mechanical Shock.	No discontinuities of 1 microsecond or longer duration. See Note (a).	EIA-364-27, Condition H; Subject mated specimens to 30 G's half-sine shock pulses of 11 milliseconds duration. Three shocks in each direction applied along 3 mutually perpendicular planes, 18 total shocks.									
Wire Retention Force	<table border="1"> <thead> <tr> <th>Min Force</th> <th>Wire Size</th> <th>Stranding</th> </tr> </thead> <tbody> <tr> <td>45N</td> <td>18AWG/0.75mm<sup>2</sup></td> <td>Solid, Tin Dipped Stranded</td> </tr> <tr> <td>40N</td> <td>20AWG/0.50mm<sup>2</sup></td> <td>Solid, Tin Dipped Stranded</td> </tr> </tbody> </table>	Min Force	Wire Size	Stranding	45N	18AWG/0.75mm <sup>2</sup>	Solid, Tin Dipped Stranded	40N	20AWG/0.50mm <sup>2</sup>	Solid, Tin Dipped Stranded	EIA-364-29, Method A; Apply an axial load as specified at a maximum rate of 25.4 mm per minute. The specified force shall be maintained for 60+/-1 seconds.
Min Force	Wire Size	Stranding									
45N	18AWG/0.75mm <sup>2</sup>	Solid, Tin Dipped Stranded									
40N	20AWG/0.50mm <sup>2</sup>	Solid, Tin Dipped Stranded									
Connector Mating/Un-Mating Torque	4.0 N-m maximum	EIA-364-13; With a 55.6N compression force applied to the PCB module or sealing cap, measure torque necessary to mate or un-mate a fully populated connector assembly.									

Receptacle Mounting Torque Resistance	30-degree rotation maximum	EIA-364-13; With a 55.6N compression force applied to the PCB module or sealing cap, apply a 5.0 N-m torque to receptacle and mating part, then evaluate the amount of rotation the receptacle exhibits relative to the original mounting location.
Durability.	See Note (a)	EIA-364-9; Mate and un-mate specimens for 10 cycles at a maximum rate of 360 cycles per hour.
Impact	See Note (a)	IEC 62262; Subject receptacle and mating part sealing cap to IK09(10 Joule) impact.
<b>ENVIRONMENTAL</b>		
Thermal Shock.	See Note (a)	EIA-364-32; Subject mated specimens to 150 cycles between -40 and 90°C with 30-minute dwells at temperature extremes and 1-minute transition between temperatures.
Humidity/Temperature Cycling.	See Note (a)	EIA-364-31, Method IV; Subject mated specimens to 10 cycles (10 days) between 25 and 65°C at 80 to 100% RH
Temperature Life.	See Note (a)	EIA-364-17, Method A; Subject mated specimens to 100°C for 500 hours.
Temperature Life - IP	See Note (a)	EIA-364-17, Method A; Subject mated specimens to 90°C for 240 hours.
Humidity Freeze	See Note (a)	IEC 61215, 2 <sup>nd</sup> Edition 2005-04,10.12.3; Subject mated specimens to 10 cycles between -40 and 90°C 85% RH
Ingress Protection (IP 6X)	No ingress of dust allowed within any sealed area of the connector.	IEC-60529, IP6X
Ingress Protection (IP X6)	No ingress of water allowed within any sealed area of the connector.	IEC-60529, IPX6
Salt Spray	No ingress of salt spray allowed within any sealed area of the connector.	IEC 60512-11-6 Exposure time is 240 hours. Test receptacle mated to a sealing cap.

**NOTE: (a)** Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.

**Figure 1**

3.4. Product Qualification and Requalification Test Sequence

TEST OR EXAMINATION	TEST GROUP (b)											
	A	B	C	D1	D2	E	F	G	H	J1	J2	K
	TEST SEQUENCE (c)											
Initial examination of product	1	1	1	1	1	1	1	1	1	1	1	1
LLCR	2,6	2,5,7	2, 8									
Insulation Resistance			3,9									
Withstanding Voltage - Internal			4,10									
Temperature Rise vs Current		3										
Random Vibration	4											
Mechanical Shock	5											
Wire Retention Force							2					
Impact								2				
Mating Torque									2			
Un-Mating Torque									3			
Receptacle Mounting Torque Resistance												2
Humidity Freeze										2	2	
Durability	3											
Thermal Shock			6									
Humidity/Temperature Cycling		4(d)	7									
Temperature Life		6										
Temperature Life – IP				2	2							
Ingress Protection (IP6X)				3						3		
Ingress Protection (IPX6)					3			3			3	
Withstand Voltage - External			5,11									
Salt Spray						2						
Final examination of product	7	8	12	4	4	3	3	4	4	4	4	3

**NOTES**

(b)See paragraph 4.1.A

(c)Numbers indicate sequence in which tests are performed.

(d)Precondition with 2 durability cycles.

**Figure 2**

#### 4. QUALITY ASSURANCE PROVISIONS

##### 4.1 Qualification Testing

##### A. Specimen Selection

Specimens shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. Minimum specimen quantities are shown in Figure 3.

Specimen Description	<i>Test Group Quantity (Minimum)</i>											
	A	B	C	D1	D2	E	F	G	H	J1	J2	K
2363638-1, receptacle	4	8	6	6	6	5	20	5	5	5	5	5
2213795-1, sealing cap				3	3	5		5		2	2	5
2213837-1, 40mm base									5			
2213831-2, 80mm base	4	8	6	3	3					3	3	
1-2328823-2, 80mm med. dome	4			3	3					3	3	
Module Wt. (45 g min.)	4											
18AWG/0.75 mm <sup>2</sup> Solid Copper Wire	8	8	12				20					
20AWG/0.5 mm <sup>2</sup> Solid Copper Wire	8	8	12				20					
18AWG/0.75 mm <sup>2</sup> Tin Dipped Stranded Copper Wire		8					20					
20AWG/0.5 mm <sup>2</sup> Tin Dipped Stranded Copper Wire		8					20					

Figure 3

##### B. Test Sequence

Qualification inspection shall be verified by testing specimens as specified in Figure 2.

##### 4.2. Requalification Testing

If changes significantly affecting form, fit or function are made to the product or manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of the original testing sequence as determined by development/product, quality and reliability engineering.

#### 4.3. Acceptance

Acceptance is based on verification that the product meets the requirements of Figure 1. Failures attributed to equipment, test setup or operator deficiencies shall not disqualify the product. If product failure occurs, corrective action shall be implemented, and specimens resubmitted for qualification. Testing to confirm corrective action is required before resubmittal.

#### 4.4. Quality Conformance Inspection

The applicable quality inspection plan shall specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

